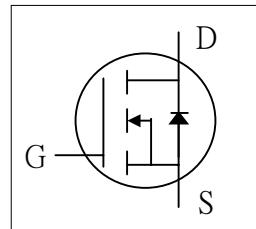
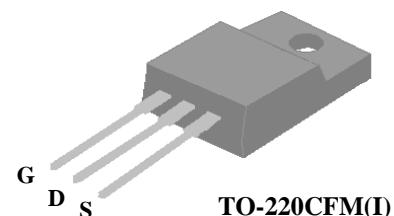




- ▼ 100% Avalanche Test
- ▼ Fast Switching Characteristic
- ▼ Simple Drive Requirement
- ▼ RoHS Compliant & Halogen-Free



$BV_{DSS}$	650V
$R_{DS(ON)}$	0.75Ω
$I_D^4$	9A



## Description

AP09N70 series are from Advanced Power innovative design and silicon process technology to achieve the lowest possible on-resistance and fast switching performance. It provides the designer with an extreme efficient device for use in a wide range of power applications.

The TO-220CFM package is widely preferred for all commercial-industrial through hole applications. The mold compound provides a high isolation voltage capability and low thermal resistance between the tab and the external heat-sink.

## Absolute Maximum Ratings@ $T_j=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Rating	Units
$V_{DS}$	Drain-Source Voltage	650	V
$V_{GS}$	Gate-Source Voltage	+30	V
$I_D @ T_c=25^\circ\text{C}$	Drain Current, $V_{GS} @ 10\text{V}^4$	9	A
$I_D @ T_c=100^\circ\text{C}$	Drain Current, $V_{GS} @ 10\text{V}^4$	5	A
$I_{DM}$	Pulsed Drain Current <sup>1</sup>	40	A
$P_D @ T_c=25^\circ\text{C}$	Total Power Dissipation	42	W
	Linear Derating Factor	0.34	W/°C
$E_{AS}$	Single Pulse Avalanche Energy <sup>2</sup>	40.5	mJ
$I_{AR}$	Avalanche Current	9	A
$T_{STG}$	Storage Temperature Range	-55 to 150	°C
$T_j$	Operating Junction Temperature Range	-55 to 150	°C

## Thermal Data

Symbol	Parameter	Value	Units
$R_{thj-c}$	Maximum Thermal Resistance, Junction-case	3	°C/W
$R_{thj-a}$	Maximum Thermal Resistance, Junction-ambient	65	°C/W



## Electrical Characteristics @ $T_j=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}$ , $I_D=1\text{mA}$	650	-	-	V
$\Delta \text{BV}_{\text{DSS}}/\Delta T_j$	Breakdown Voltage Temperature Coefficient	Reference to $25^\circ\text{C}$ , $I_D=1\text{mA}$	-	0.6	-	$\text{V}/^\circ\text{C}$
$R_{\text{DS}(\text{ON})}$	Static Drain-Source On-Resistance <sup>3</sup>	$V_{\text{GS}}=10\text{V}$ , $I_D=4.5\text{A}$	-	-	0.75	$\Omega$
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}$ , $I_D=250\text{\mu A}$	2	-	4	V
$g_{\text{fs}}$	Forward Transconductance	$V_{\text{DS}}=50\text{V}$ , $I_D=4.5\text{A}$	-	4.5	-	S
$I_{\text{DSS}}$	Drain-Source Leakage Current	$V_{\text{DS}}=480\text{V}$ , $V_{\text{GS}}=0\text{V}$	-	-	100	$\text{\mu A}$
$I_{\text{GSS}}$	Gate-Source Leakage	$V_{\text{GS}}=\pm 30\text{V}$ , $V_{\text{DS}}=0\text{V}$	-	-	$\pm 100$	nA
$Q_g$	Total Gate Charge	$I_D=9\text{A}$	-	44	-	nC
$Q_{\text{gs}}$	Gate-Source Charge	$V_{\text{DS}}=480\text{V}$	-	11	-	nC
$Q_{\text{gd}}$	Gate-Drain ("Miller") Charge	$V_{\text{GS}}=10\text{V}$	-	12	-	nC
$t_{\text{d}(\text{on})}$	Turn-on Delay Time	$V_{\text{DD}}=300\text{V}$	-	19	-	ns
$t_r$	Rise Time	$I_D=9\text{A}$	-	21	-	ns
$t_{\text{d}(\text{off})}$	Turn-off Delay Time	$R_G=10\Omega$	-	56	-	ns
$t_f$	Fall Time	$V_{\text{GS}}=10\text{V}$	-	24	-	ns
$C_{\text{iss}}$	Input Capacitance	$V_{\text{GS}}=0\text{V}$	-	2660	-	pF
$C_{\text{oss}}$	Output Capacitance	$V_{\text{DS}}=25\text{V}$	-	170	-	pF
$C_{\text{rss}}$	Reverse Transfer Capacitance	f=1.0MHz	-	10	-	pF

## Source-Drain Diode

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
$I_s$	Continuous Source Current ( Body Diode )	$V_D=V_G=0\text{V}$ , $V_S=1.5\text{V}$	-	-	9	A
$I_{\text{SM}}$	Pulsed Source Current ( Body Diode ) <sup>1</sup>		-	-	40	A
$V_{\text{SD}}$	Forward On Voltage <sup>3</sup>	$T_j=25^\circ\text{C}$ , $I_s=9\text{A}$ , $V_{\text{GS}}=0\text{V}$	-	-	1.5	V

### Notes:

1. Pulse width limited by Max. junction temperature.
2. Starting  $T_j=25^\circ\text{C}$ ,  $V_{\text{DD}}=50\text{V}$ ,  $L=1\text{mH}$ ,  $R_G=25\Omega$ ,  $I_{\text{AS}}=9\text{A}$ .
3. Pulse test
4. Ensure that the junction temperature does not exceed  $T_{\text{jmax}}$ .

THIS PRODUCT IS SENSITIVE TO ELECTROSTATIC DISCHARGE, PLEASE HANDLE WITH CAUTION.

USE OF THIS PRODUCT AS A CRITICAL COMPONENT IN LIFE SUPPORT OR OTHER SIMILAR SYSTEMS IS NOT AUTHORIZED.

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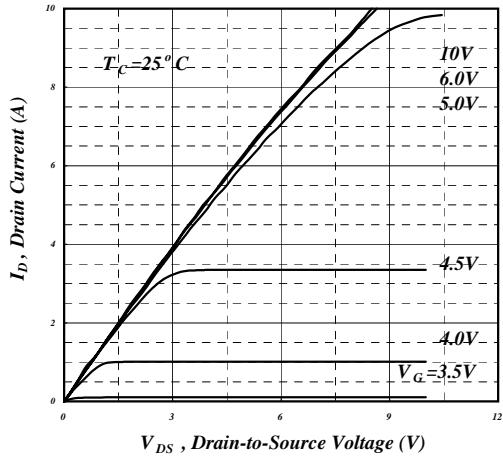


Fig 1. Typical Output Characteristics

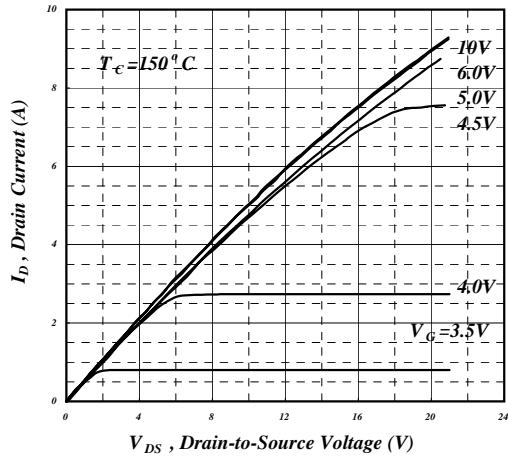


Fig 2. Typical Output Characteristics

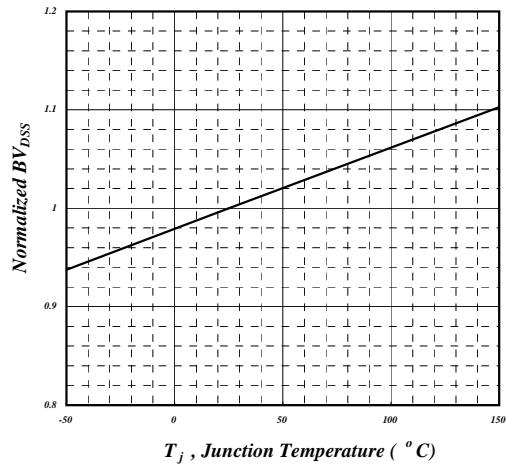
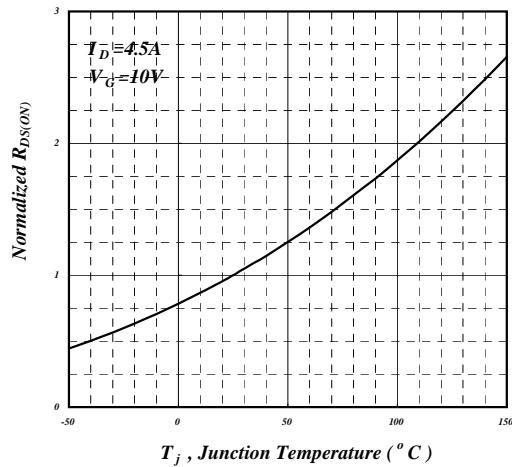
Fig 3. Normalized  $BV_{DSS}$  v.s. Junction Temperature

Fig 4. Normalized On-Resistance v.s. Junction Temperature

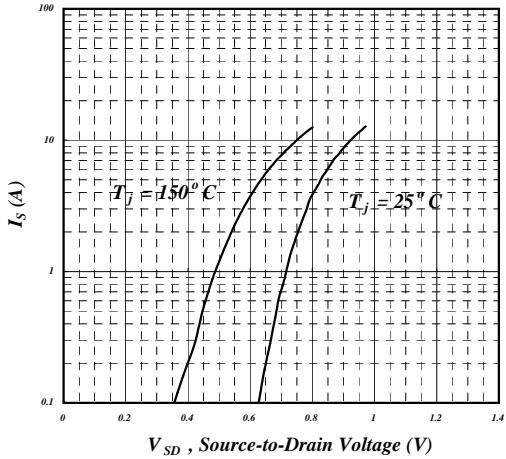


Fig 5. Forward Characteristic of Reverse Diode

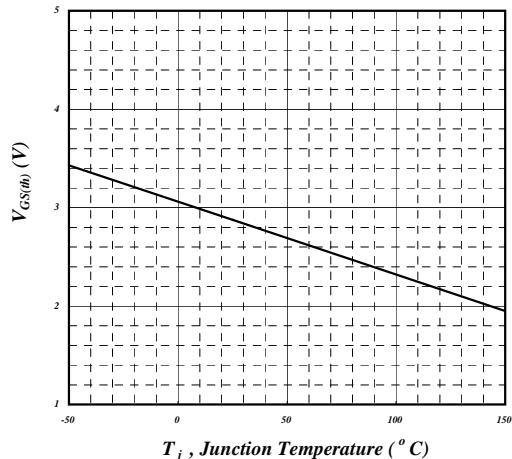
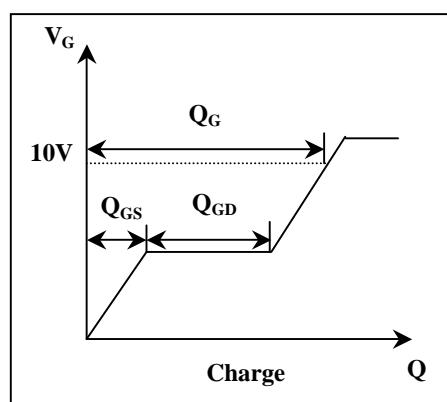
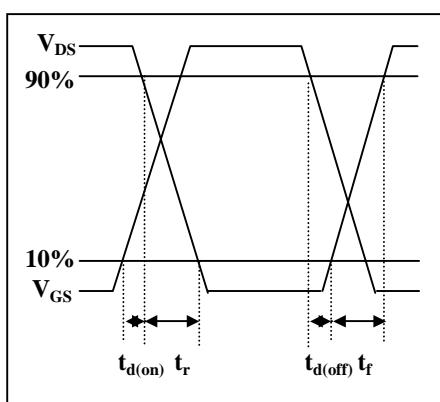
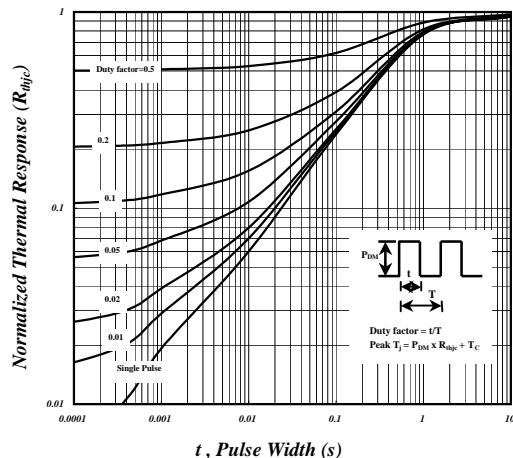
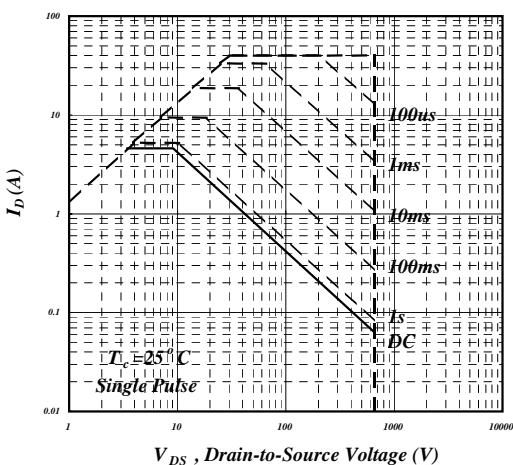
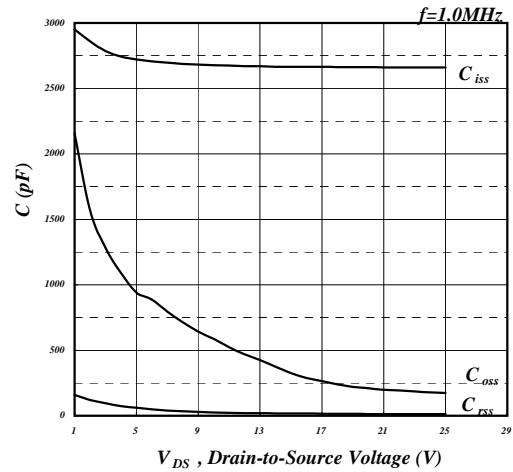
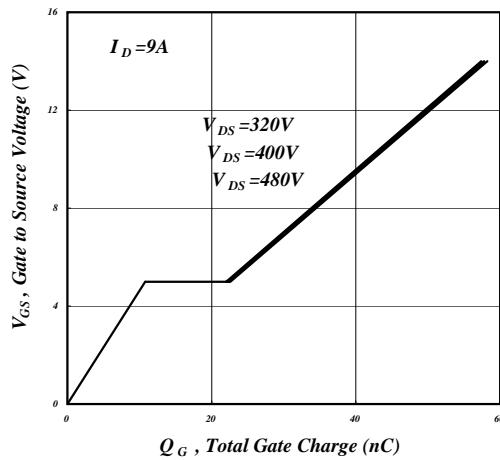


Fig 6. Gate Threshold Voltage v.s. Junction Temperature





## **MARKING INFORMATION**

